

Article

# Fourier Features and Machine Learning for Contour Profile Inspection in CNC Milling Parts: A Novel Intelligent Inspection Method (NIIM)

Manuel Meraz Méndez <sup>1,\*</sup>, Juan A. Ramírez Quintana <sup>2†</sup>, Elva Lilia Reynoso Jardón <sup>3,†</sup>,  
Manuel Nandayapa <sup>3,†</sup> and Osslán Osiris Vergara Villegas <sup>3,†</sup>

<sup>1</sup> Department of Industrial Maintenance, Technological University of Chihuahua, Chihuahua 31313, Mexico

<sup>2</sup> Department of Digital Signal Processing, TecNM-Technological Institute of Chihuahua, Chihuahua 31200, Mexico; juan.rq@chihuahua.tecnm.mx

<sup>3</sup> Department of Industrial Engineering, Autonomous University of Juarez City, Ciudad Juárez 32310, Mexico; elva.reynoso@uacj.mx (E.L.R.J.); mnandaya@uacj.mx (M.N.); overgara@uacj.mx (O.O.V.V.)

\* Correspondence: mmeraz@utch.edu.mx

† These authors contributed equally to this work.

